Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/552,469	MIYAWAKI ET AL.	
Examiner	Art Unit	
Truc T. T. Nguyen	2833	

SEARCHED						
Class	Subclass	Date	Examiner			
439	260 630-633	4/14/2007	TN			
235	441	4/14/2007	TN			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
see sea	rch print	4/14/2007	TN	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
·	DATE	EXMR	
439/260, 630-633	4/14/2007	TN	
235/441	4/14/2007	TN	
 			
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